



## CTL0262PS-R3

### P-Channel Enhancement MOSFET

#### Features

- Drain-Source Breakdown Voltage  $V_{DSS}$  -20 V
- Drain-Source On-Resistance  
 $R_{DS(ON)}$  76m $\Omega$ , at  $V_{GS} = -4.5V$ ,  $I_D = -3.4A$   
 $R_{DS(ON)}$  97m $\Omega$ , at  $V_{GS} = -2.5V$ ,  $I_D = -2.4A$   
 $R_{DS(ON)}$  140m $\Omega$ , at  $V_{GS} = -1.8V$ ,  $I_D = -1.7A$
- Continuous Drain Current at  $T_C=25^\circ C$   $I_D = -3.4A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

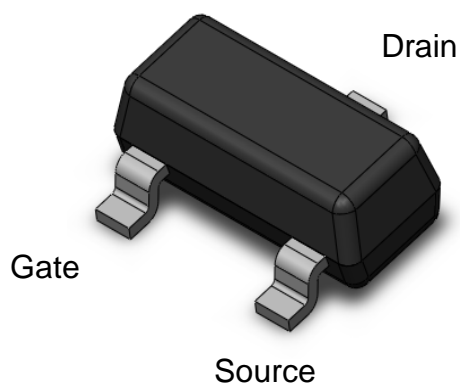
#### Applications

- Power Management
- Lithium Ion Battery

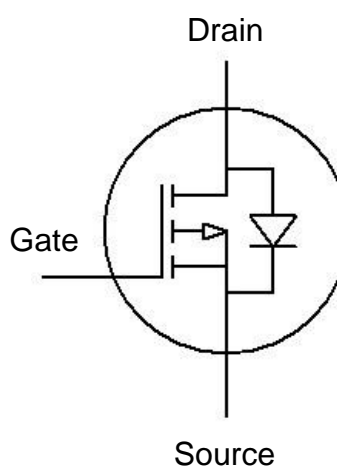
#### Description

The CTL0262PS-R3 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management .

#### Package Outline



#### Schematic



**Absolute Maximum Rating at 25°C**

Symbol	Parameters	Test Conditions	Min	Notes
V <sub>DS</sub>	Drain-Source Voltage	-20	V	
V <sub>GS</sub>	Gate-Source Voltage	±12	V	
I <sub>D</sub>	Continuous Drain Current	-3.4	A	1
I <sub>DM</sub>	Pulsed Drain Current	-14	A	1
P <sub>D</sub>	Total Power Dissipation	1.25	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C	

**Thermal Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>ΘJA4</sub>	Thermal Resistance Junction-Ambient (t=10s)		--	105	--	°C/W	1,4



P-Channel Enhancement MOSFET

**Electrical Characteristics**  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

**Static Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B <sub>VDS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-20	-	-	V	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V	-	-	-1	μA	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±12V, V <sub>DS</sub> = 0V	-	-	±100	nA	

**On Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>DS(ON)</sub>	Drain-Source On-Resistance	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -3.4A	-	76	95	mΩ	3
		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -2.4A	-	97	120	mΩ	
		V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -1.7A	-	140	180	mΩ	
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = -250μA	-0.4	---	-0.9	V	3

**Dynamic Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C <sub>ISS</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = -6V f = 1MHz	-	1100	-	pF	
C <sub>OSS</sub>	Output Capacitance		-	200	-		
C <sub>RSS</sub>	Reverse Transfer Capacitance		-	40	-		

**Switching Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
T <sub>D(ON)</sub>	Turn-On Delay Time	V <sub>DS</sub> = -6V, V <sub>GS</sub> = -4.5V, R <sub>G</sub> = 6Ω, R <sub>L</sub> = 6Ω,	-	43	-	ns	
T <sub>R</sub>	Rise Time		-	30	-		
T <sub>D(OFF)</sub>	Turn-Off Delay Time		-	56	-		
T <sub>F</sub>	Fall Time		-	6.2	-		
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = -6V, V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -2.8A	-	10	-	nC	
Q <sub>GS</sub>	Gate-Source Charge		-	2.4	-		
Q <sub>GD</sub>	Gate-Drain Charge		-	2.2	-		

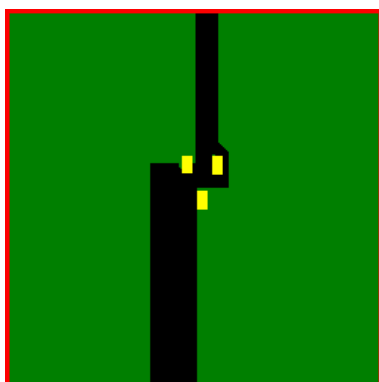


**Drain-Source Diode Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V <sub>SD</sub>	Body Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = -1.5A	-	-0.8	-1.2	V	
I <sub>SD</sub>	Body Diode Continuous Current		-	-	-1.5	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4  
25.4 x 25.4 mm .  
2 Oz Copper

Actual Size

3. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



### Typical Characteristic Curves

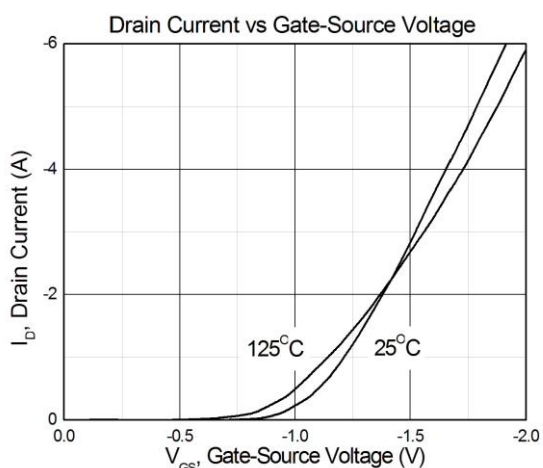


Figure 1

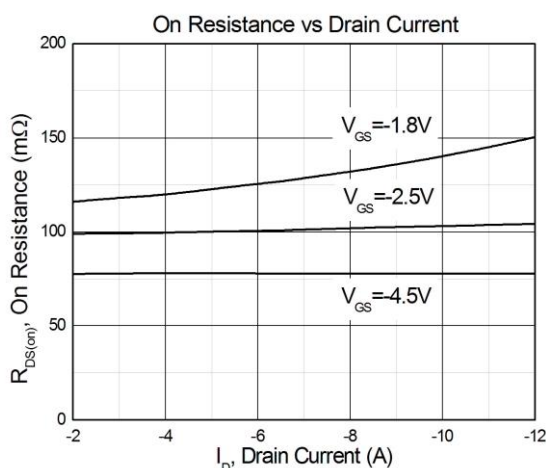


Figure 2

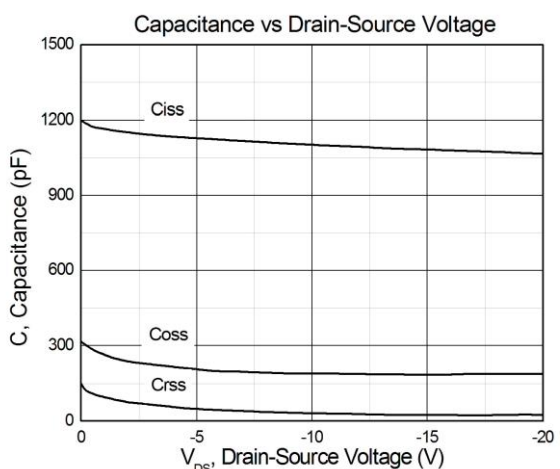


Figure 3

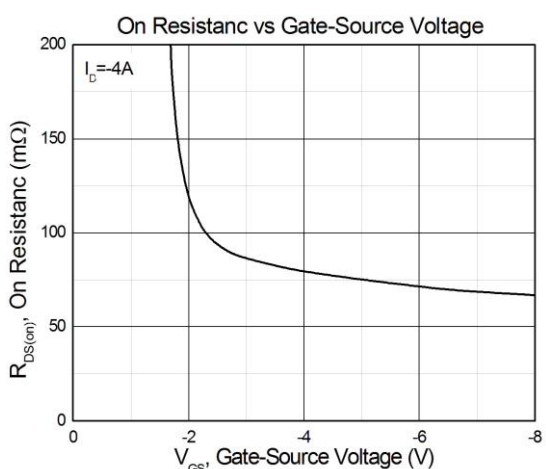


Figure 4

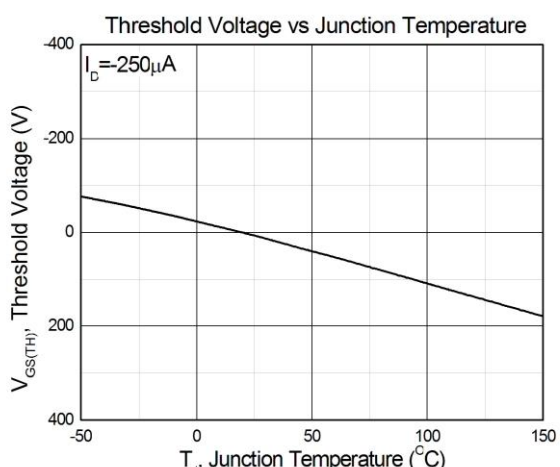


Figure 5

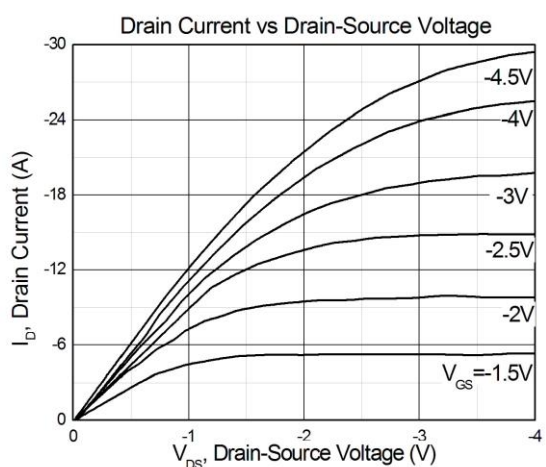


Figure 6

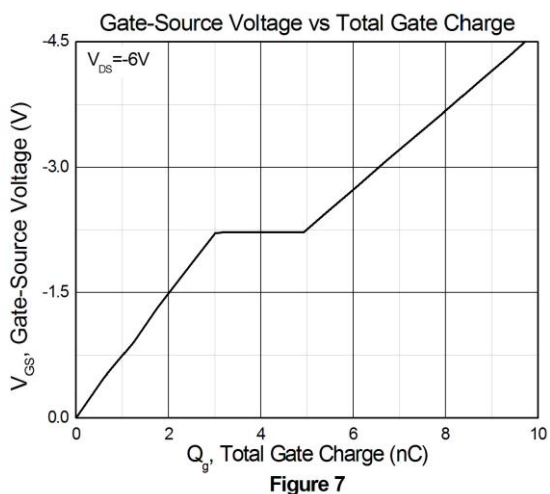


Figure 7

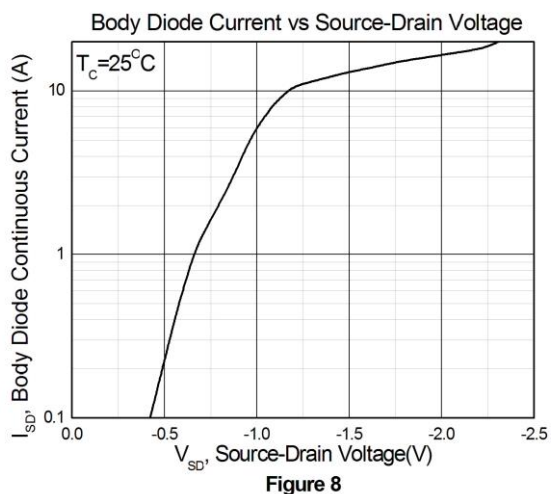


Figure 8



Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

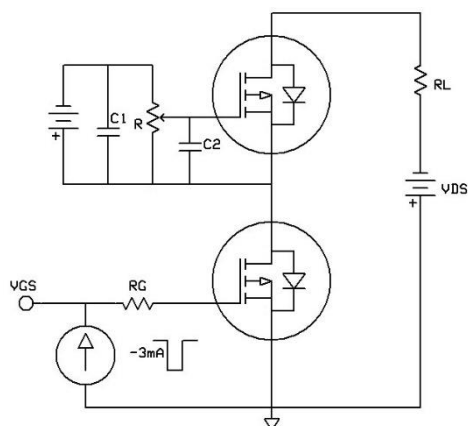


Figure 10: Gate Charge Waveform

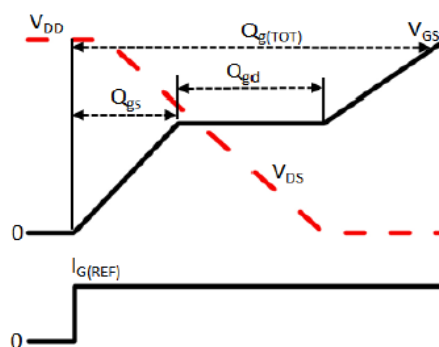


Figure 11: Switching Time Test Circuit

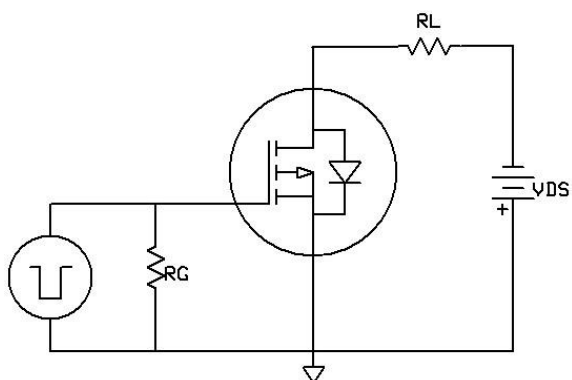
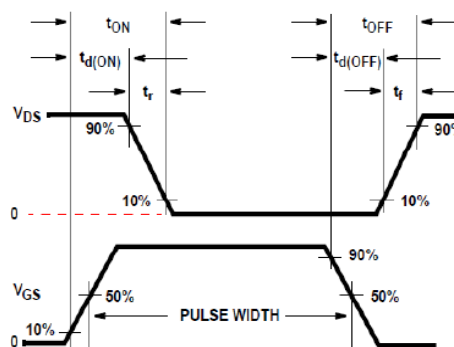
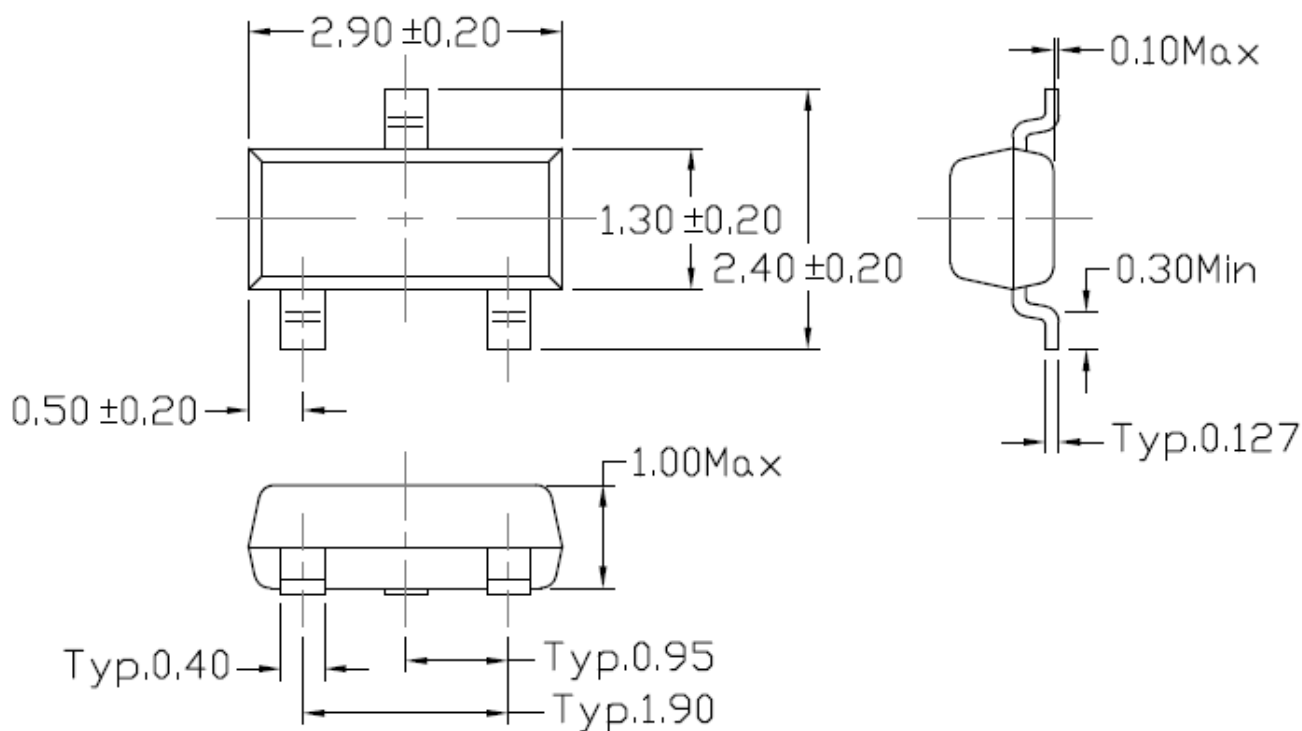


Figure 12: Switching Time Waveform



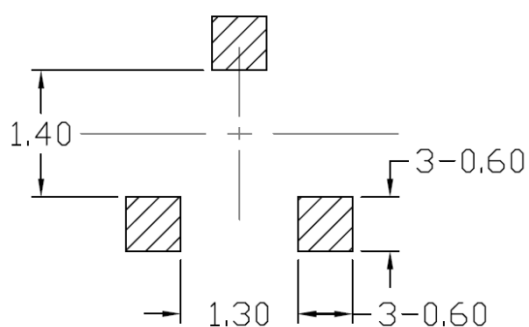


Package Dimension (SOT-23)



Note: Dimensions in mm

Recommended pad layout for surface mount leadform

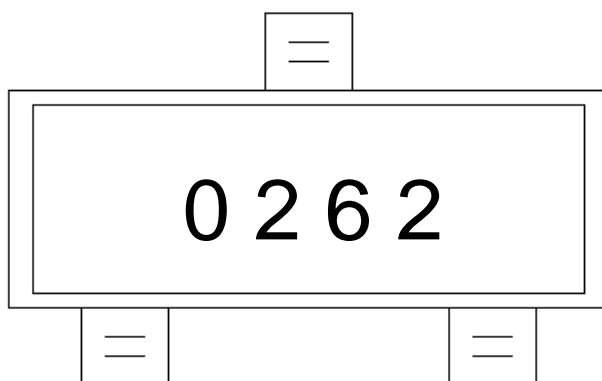


Note: Dimensions in mm





### Marking Information



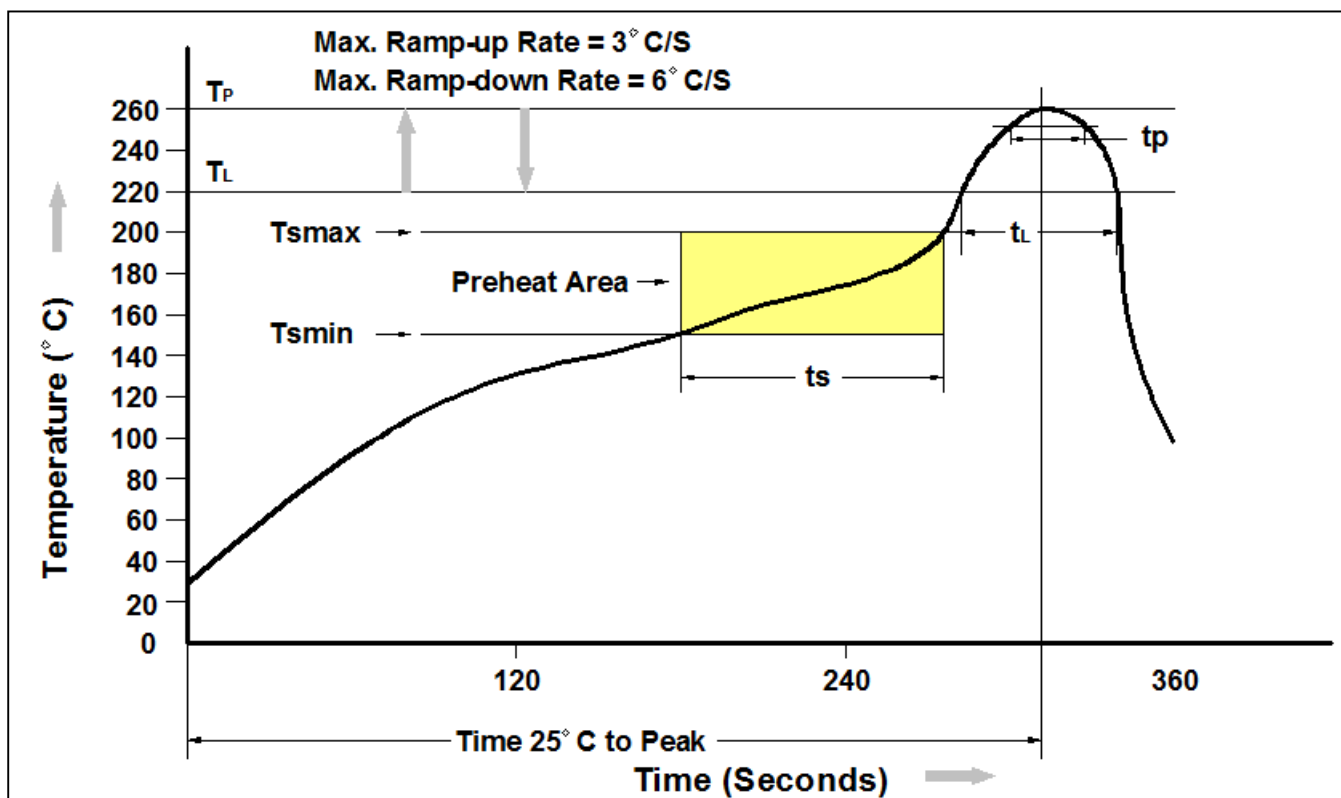
0262: Device Number

### Ordering Information

Part Number	Description	Quantity
CTL0262PS-R3	SOT-23 Reel	3000 pcs



### Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T <sub>smin</sub> )	150°C
Temperature Max. (T <sub>smax</sub> )	200°C
Time (t <sub>s</sub> ) from (T <sub>smin</sub> to T <sub>smax</sub> )	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217°C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t <sub>P</sub> ) within 5°C of 260°C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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